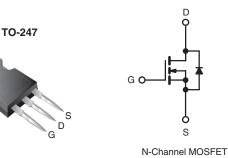
Vishay Siliconix



Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	900				
R _{DS(on)} (Ω)	V _{GS} = 10 V	2.5			
Q _g (Max.) (nC)	120				
Q _{gs} (nC)	16				
Q _{gd} (nC)	67				
Configuration	Single				



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mouting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.

ORDERING INFORMATION	
Package	TO-247
Lead (Pb)-free	IRFPF40PbF
	SiHFPF40-E3
SnPb	IRFPF40
	SiHFPF40

ABSOLUTE MAXIMUM RATINGS $T_C = 25 \degree C$, unless otherwise noted							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			V _{DS}	900	N		
Gate-Source Voltage			V _{GS}	± 20	V		
Continuous Drain Current	V _{GS} at 10 V	$T_{C} = 25 \degree C$ $T_{C} = 100 \degree C$	- I _D -	4.7			
		$T_C = 100 ^{\circ}C$		2.9	А		
Pulsed Drain Current ^a			I _{DM}	19	1		
Linear Derating Factor				1.2	W/°C		
Single Pulse Avalanche Energy ^b			E _{AS}	500	mJ		
Repetitive Avalanche Current ^a			I _{AR}	4.7	A		
Repetitive Avalanche Energy ^a			E _{AR}	15	mJ		
Maximum Power Dissipation	T _C =	25 °C	PD	P _D 150			
Peak Diode Recovery dV/dtc			dV/dt	1.5	V/ns		
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	for	for 10 s		300 ^d			
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in		
			-	1.1	N · m		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 50 V, starting T_J = 25 °C, L = 42 mH, R_G = 25 Ω , I_{AS} = 4.7 A (see fig. 12).

c. $I_{SD} \leq 4.7$ A, dl/dt ≤ 110 A/µs, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

COMPLIANT

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THERMAL RESISTANCE RAT	TINGS								
PARAMETER	SYMBOL	TYP.		MAX.		UNIT			
Maximum Junction-to-Ambient	R _{thJA}	- 40 0.24 -							
Case-to-Sink, Flat, Greased Surface	R _{thCS}				°C/W				
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.83							
SPECIFICATIONS $T_J = 25 \ ^{\circ}C$,	unless other	wise noted							
PARAMETER	SYMBOL	TEST	CONDITIO	ONS	MIN.	TYP.	MAX.	UNIT	
Static		•						•	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0	V, I _D = 28	50 µA	900	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference t	o 25 °C, I	_D = 1 mA	-	1.0	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$			2.0	-	4.0	V	
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V			-	-	± 100	nA	
Zaus Osta Maltana Dusia Ourrant	V _{DS} = 900 V, V _{GS} = 0 V	= 0 V	-	-	100	μΑ			
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 720 V, V _{GS} = 0 V, T _J = 125 °C		-	-		500		
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D	= 2.8 A ^b	-	-	2.5	Ω	
Forward Transconductance	g fs	V _{DS} = 50	0 V, I _D = 2	2.8 A ^b	2.5	-	-	S	
Dynamic									
Input Capacitance	C _{iss}	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	1600	-	pF		
Output Capacitance	C _{oss}			-	180	-			
Reverse Transfer Capacitance	C _{rss}			-	63	-			
Total Gate Charge	Qg				-	-	120		
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V} \qquad \begin{array}{c} I_{D} = 4.7 \text{ A}, V_{DS} = 360 \text{ V},\\ \text{see fig. 6 and } 13^{b} \end{array}$			-	-	16	nC	
Gate-Drain Charge	Q _{gd}			g. o and to	-	-	67		
Turn-On Delay Time	t _{d(on)}				-	15	-		
Rise Time	t _r	$V_{DD}=450~V,~I_D=4.7~A~, \label{eq:nd} R_G=9.1~\Omega,~R_D=95~\Omega,~see~fig.~10^b$		-	36	-	ns		
Turn-Off Delay Time	t _{d(off)}			-	110	-			
Fall Time	t _f			-	32	-			
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH		
Internal Source Inductance	L _S			-	13	-			
Drain-Source Body Diode Characteristic	s								
Continuous Source-Drain Diode Current	١ _S	MOSFET symbol showing the		-	-	4.7	A		
Pulsed Diode Forward Current ^a	I _{SM}	p - n junction diode			-	-		19	
Body Diode Voltage	V_{SD}	$T_J = 25 \ ^\circ C, \ I_S = 4.7 \ A, \ V_{GS} = 0 \ V^b$			-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = 4.7 \text{ A}, dl/dt = 100 \text{ A}/\mu\text{s}^b$		-	510	770	ns		
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.2	3.3	μC		
Forward Turn-On Time									

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



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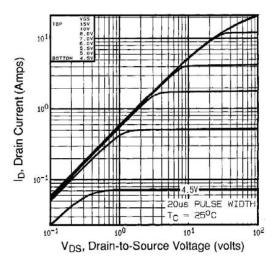


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

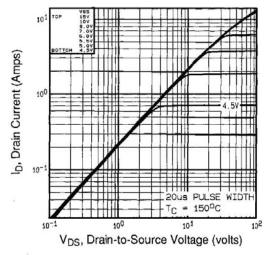


Fig. 2 - Typical Output Characteristics, T_C = 150 $^\circ C$

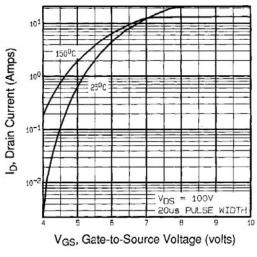


Fig. 3 - Typical Transfer Characteristics

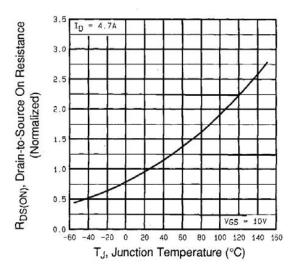


Fig. 4 - Normalized On-Resistance vs. Temperature

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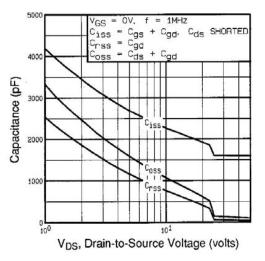


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

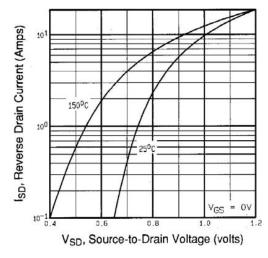


Fig. 7 - Typical Source-Drain Diode Forward Voltage

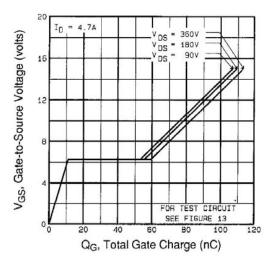


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

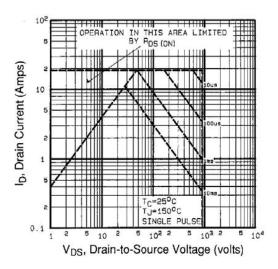


Fig. 8 - Maximum Safe Operating Area



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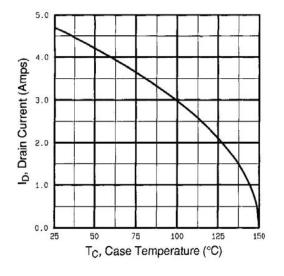


Fig. 9 - Maximum Drain Current vs. Case Temperature

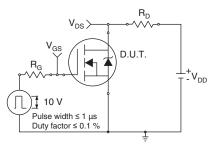


Fig. 10a - Switching Time Test Circuit

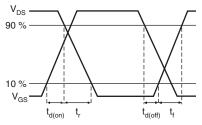
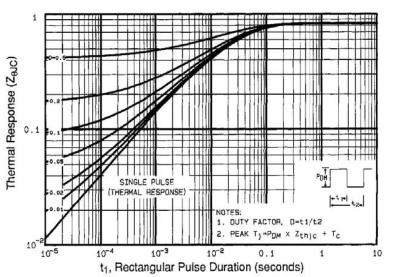
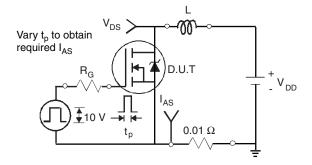
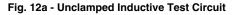


Fig. 10b - Switching Time Waveforms









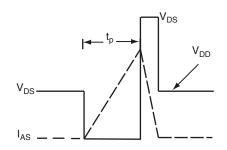


Fig. 12b - Unclamped Inductive Waveforms

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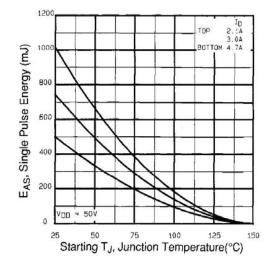


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

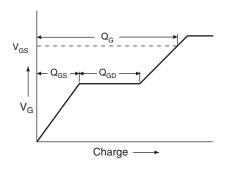


Fig. 13a - Basic Gate Charge Waveform

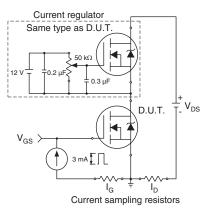
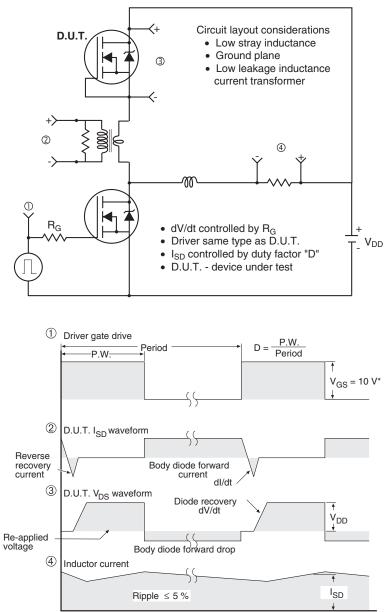


Fig. 13b - Gate Charge Test Circuit



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Peak Diode Recovery dV/dt Test Circuit

* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

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